IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor: John L. Fulton, et al.	)	Art Unit: 1746
Serial No:10/783,249	)	Examiner: Michail Kornakov
Filed: 2/19/2004	)	File No: 14138-J
For: PROCESS AND APPARATUS FOR REMOVING RESIDUES FROM SEMICONDUCTOR SUBSTRATES	)	Date: February 8, 2005

INFORMATION DISCLOSURE STATEMENT
(References – See attached forms PTO/SB/08A and PTO/SB/08B)

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Attached hereto are Forms PTO/SB/08A and PTO/SB/08B listing documents believed to be relevant to the subject application. It is respectfully requested that these documents be considered by the examiner and an initialed copy of each form be returned to the undersigned.

This disclosure statement should not be construed as a representation that a search has been made or that no other material information exists, as defined in 37 C. F. R. § 1.56(a). No admission is made regarding whether any of the submitted references is prior art.

It is believed that this disclosure complies with the requirements of 37 C. F. R. §§ 1.56, 1.97, 1.98, and the Manual of Patent Examining Procedures § 609. If for some reason the examiner considers otherwise, it is respectfully requested that the undersigned be called so that any deficiencies can be remedied.

This IDS is either being submitted within the 3 month deadline or prior to the 1st Office Action, and no fees are believed to be required. However, if any fees are required for consideration of this paper, the Director is hereby authorized to charge our Deposit Account No. 02-1275.

Respectfully submitted,

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PTO/SB/08A (08-03)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of 9

Complete if Known	
Application Number	10/783,249
Filing Date	02/19/2004
First Named Inventor	John L. Fulton
Art Unit	1746
Examiner Name	Michail Kornakov
Attorney Docket Number	14138-J

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Document Number Number-Kind Code[2] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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		WO 01/51866 A1	07-19-2001	Semitool, Inc.		
		WO 01/51990 A1	07-19-2001	Semiconductor		
		WO 01/82368 A2	11-01-2001	Tokyo Electron		

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		WO 95/16280	06/15/1995	Sec. of State		

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Attorney Docket Number	14138-J

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Examiner Initials*	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
		CONSANI, K.A., Observations on the Solubility of Surfactants and Related Molecules in Carbon Dioxide at 50 °C, Journal of Supercritical Fluids, 1990, 3, 51-65	
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		JI, M., et at., Synthesizing and Dispersing Silver Nanoparticles in a Water-in-Supercritical Carbon Dioxide Microemulsion, J. Am. Chem Soc 1999, 121, 2631-2632	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 9 of 9

Complete if Known	
Application Number	10/783,249
Filing Date	02/19/2004
First Named Inventor	John L. Fulton
Art Unit	1746
Examiner Name	Michail Kornakov
Attorney Docket Number	14138-J

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		YEE, G.G., et al., Fourier Transform Infrared Spectroscopy of Molecular Interactions of Heptafluoro-1-butanol or 1-Butanol in Supercritical.., J. Phys Chem 1992, 96, 6172-6181	
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor: John L. Fulton, et al.	)	Art Unit: 1746
Serial No:10/783,249	)	Examiner: Michail Kornakov
Filed: 2/19/2004	)	File No: 14138-J
For: PROCESS AND APPARATUS FOR REMOVING RESIDUES FROM SEMICONDUCTOR SUBSTRATES	)	Date: February 8, 2005

CERTIFICATE OF MAILING

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